



Krytyczne Zjawiska na Powierzchniach i Interfejsach: Ulotne Rozpraszanie Rentgenowskie i Neutronowe

Indeks: **710825** Producent: **Springer** Kod producenta: **9783662149751**

Cena: **218.46 zł**

Opis

Critical Phenomena at Surfaces and Interfaces: Evanescent X-Ray and Neutron Scattering (Springer Tracts in Modern Physics, Band 126)

Producent: Springer

- temat:** Laser physics, Materials science, Physical chemistry, Testing of materials, SCIENCE / Physics / Crystallography, Science / Chemistry / Physical & Theoretical, Science / Physics / Optics & Light, TECHNOLOGY & ENGINEERING / Materials Science / General, TECHNOLOGY & ENGINEERING / Materials Science / Thin Films, Surfaces & Interfaces, TECHNOLOGY & ENGINEERING / Optics, Technology & Engineering / Lasers & Photonics, Technology & Engineering/Optics, ANF: Science, Characterization and Analytical Technique, Chemie, Chemistry, Chemistry - Physical & Theoretical, Chemistry, Physical organic, Crystallography, Crystallography and Scattering Methods, Elektrizität, Magnetismus, Optik, General, Germany, HC, HC/Chemie/Physikalische Chemie, HC/Physik, Astronomie/Elektrizität, Magnetismus, Optik, HC/Technik/Maschinenbau, Fertigungstechnik, Hardcover, Softcover, Hardcover, Softcover / Physik, Astronomie/Elektrizität, Magnetismus, Optik, Laser, Laser physics, Laserphysik, Lasers & Photonics, Maschinenbau, Fertigungstechnik, Materials Science - Thin Films, Surfaces & Interfaces, Materials science, Materialwissenschaft, Non-Fiction, Optics, Optics & Light, Phasenübergänge; Röntgenstrahlung und Neutronenstreuung; Streuung; X-ray; diffraction; oberflächeninduzierte kritische Phänomene; phase transitions; scattering; specular reflection; surface; surface-induced critical phenomea; synchrotron radiation; x-ray and neutron scattering, Phasenübergänge, Phasenübergänge; Röntgenstrahlung und Neutronenstreuung; Streuung; diffraction; oberflächeninduzierte kritische Phänomene; Phase transitions; specular reflection; surface; surface-induced critical phenomea; synchrotron radiation, Phasenübergänge;Röntgenstrahlung und Neutronenstreuung;Streuung;X-ray;diffraction;oberflächeninduzierte kritische Phänomene;phase transitions;scattering;specular reflection;surface;surface-induced critical phenomea;synchrotron radiation;x-ray and neutron scattering, Physical & Theoretical, Physical chemistry, Physics, Physics - Crystallography, Physics - Optics & Light, Physik, Astronomie, Physikalische Chemie, Röntgenstrahlung und Neutronenstreuung, SCI/TECH, SCIENCE, SCIENCE / Chemistry / Physical & Theoretical, SCIENCE / Physics / Crystallography, SCIENCE / Physics / Optics & Light, Science/Chemistry - Physical & Theoretical, Science/Math, Science/Physics - Crystallography, Science/Physics - Optics & Light, Streuung, Surfaces (Physics), Surfaces, Interfaces and Thin Film, TECHNOLOGY & ENGINEERING, TECHNOLOGY & ENGINEERING / Lasers & Photonics, TECHNOLOGY & ENGINEERING / Materials Science / General, TECHNOLOGY & ENGINEERING / Materials Science / Thin Films, Surfaces & Interfaces, TECHNOLOGY & ENGINEERING / Optics, Technik, Technology & Engineering/Lasers & Photonics, Technology & Engineering/Materials Science - Thin Films, Surfaces & Interfaces, Technology & Engineering/Optics, Testing of materials, Thin Films, Surfaces & Interfaces, Verstehen, Werkstoffprüfung, X-ray, diffraction, oberflächeninduzierte kritische Phänomene, phase transitions, scattering, specular reflection, surface, surface-induced critical phenomea, synchrotron radiation, x-ray and neutron scattering, Laserphysik, Materialwissenschaft, Physikalische Chemie, Werkstoffprüfung,

HC/Chemie/Physikalische Chemie, HC/Physik, Astronomie/Elektrizität, Magnetismus, Optik,
HC/Technik/Maschinenbau, Fertigungstechnik, Hardcover, Softcover / Physik, Astronomie/Elektrizität, Magnetismus,
Optik

- **wiązący:** paperback
- **język:** english, english, english
- **waga przedmiotu:** 0.518 pounds
- **strony:** 160
- **słowo kluczowe tematu:** Germany, Non-Fiction, Phasenübergänge; Röntgenstrahlung und Neutronenstreuung; Streuung; X-ray; diffraction; oberflächeninduzierte kritische Phänomene; phase transitions; scattering; specular reflection; surface; surface-induced critical phenomea; synchrotron radiation; x-ray and neutron scattering, Phasenübergänge, Phasenübergänge; Röntgenstrahlung und Neutronenstreuung; Streuung; X-ray; diffraction; oberflächeninduzierte kritische Phänomene; phase transitions; scattering; specular reflection; surface; surface-induced critical phenomea; synchrotron radiation; x-ray and neutron scattering, Phasenübergänge; Röntgenstrahlung und Neutronenstreuung; Streuung; diffraction; oberflächeninduzierte kritische Phänomene; Phase transitions; specular reflection; surface; surface-induced critical phenomea; synchrotron radiation, Phasenübergänge; Röntgenstrahlung und Neutronenstreuung; Streuung; X-ray; diffraction; oberflächeninduzierte kritische Phänomene; phase transitions; scattering; specular reflection; surface; surface-induced critical phenomea; synchrotron radiation; x-ray and neutron scattering, Röntgenstrahlung und Neutronenstreuung, SCI/TECH, Science/Math, Streuung, X-ray, diffraction, oberflächeninduzierte kritische Phänomene, phase transitions
- **marka:** Springer
- **kod unspsc:** 55101500
- **kod podmiotu:** SCI016000, SCI013050, SCI053000, TEC021000, TEC021040, TEC030000, TEC019000, TEC030000, 1655, 1643, 1682, 1643, PHJL, TGM, PNR, TGMT, PHJL, TGM, PNR, TGMT
- **grupa docelowa:** Professional and scholarly
- **tom:** 126
- **numer części:** 9783662149751
- **kolor:** Yellow
- **waga opakowania przedmiotu:** 0.56 pounds
- **wydanie:** Softcover reprint of the original 1st ed. 1992
- **numer seryjny:** 126
- **zewnętrznie przypisany identyfikator produktu:** 3662149753, 9783662149751, 09783662149751
- **producent:** Springer
- **tytuł serii:** Springer Tracts in Modern Physics
- **autor:** Dosch, Helmut
- **gatunek muzyczny:** Laser physics, Physical chemistry, Testing of materials, Materials science, SCIENCE, Physics, Optics & Light, TECHNOLOGY & ENGINEERING, Lasers & Photonics, SCIENCE, Chemistry, Physical & Theoretical, SCIENCE, Physics, Crystallography, TECHNOLOGY & ENGINEERING, Materials Science, Thin Films, Surfaces & Interfaces, TECHNOLOGY & ENGINEERING, Materials Science, General, HC, Physik, Astronomie, Elektrizität, Magnetismus, Optik, HC, Chemie, Physikalische Chemie, HC, Technik, Maschinenbau, Fertigungstechnik, Laser physics, Physical chemistry, Testing of materials, Materials science
- **Data publikacji:** 2013-10-03T00:00:01Z
- **cena katalogowa uvp:** 53.49
- **numer wydania:** 1
- **nazwa przedmiotu:** Critical Phenomena at Surfaces and Interfaces: Evanescent X-Ray and Neutron Scattering (Springer Tracts in Modern Physics, Band 126)
- **data premiery:** 2013-10-03T00:00:01Z
- **data uruchomienia strony produktu:** 2013-09-18T16:47:05.418Z

Wydawca	Springer
Liczba stron	160
Język	angielski
Waga	0.518 funtów
ISBN	9783662149751
Data wydania	2013-10-03